Mission profile resolution impacts on the thermal stress and reliability of power devices in PV inverters
Sangwongwanich, Ariya; Zhou, D.; **Liivik, Elizaveta**; Blaabjerg, Frede Microelectronics reliability 2018 / p. 1003-1007
https://doi.org/10.1016/j.microrel.2018.06.094

Reliability analysis of micro-inverters considering PV module variations and degradation rates
Liivik, Elizaveta; Sangwongwanich, Ariya; Blaabjerg, Frede 2018 20th European Conference on Power Electronics and Applications (EPE'18 ECCE Europe) : Riga, Latvia, 17-21 September 2018 2018 / p. 1475-1482 : ill https://ieeexplore.ieee.org/document/8515325